Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/896,854	DEVERILL ET AL.
Examiner	Art Unit
Haresh Patel	2154

	SEARCHED		
Class	Subclass	Date	Examiner
719	318 328	213/06	H.P.
709	200-203, 217-227		
705	65,75		
718	100,101		
902	22		
719	310,313-31	8	
700	32,91		
702	182		
703	22		
705	11,22		
714	47		
709	224		
710	15-18		
715	736		
717	127,128	7	1

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
719	328	2/3/06	n.l.		
709	223				
709	202	4	1		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST, US-PAT, US-PUB, EPO, JPO, JEEE XPlore, ACM Digital INDEXTY, JEEE XPLORE, CLOSSIE.	213106	н.Р
Consulted lewis Bullook	2/2/06	H.P.
Consulted 101 Panel	2/2/06	H.P.